



L9: Analog Building Blocks

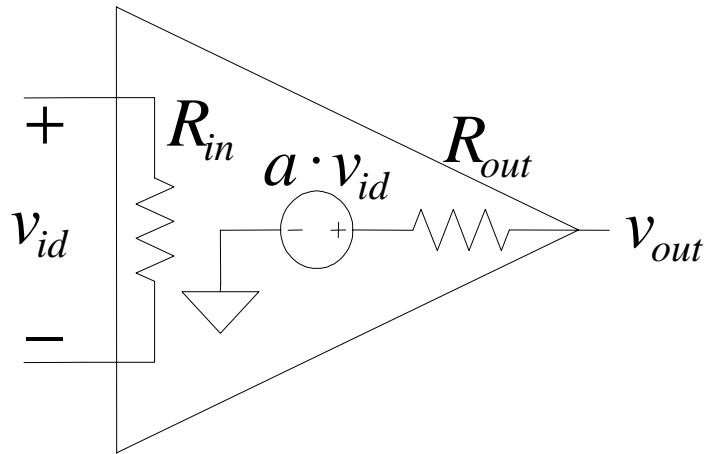
(OpAmps, A/D, D/A)



Acknowledgement: Dave Wentzloff

Introduction to Operational Amplifiers

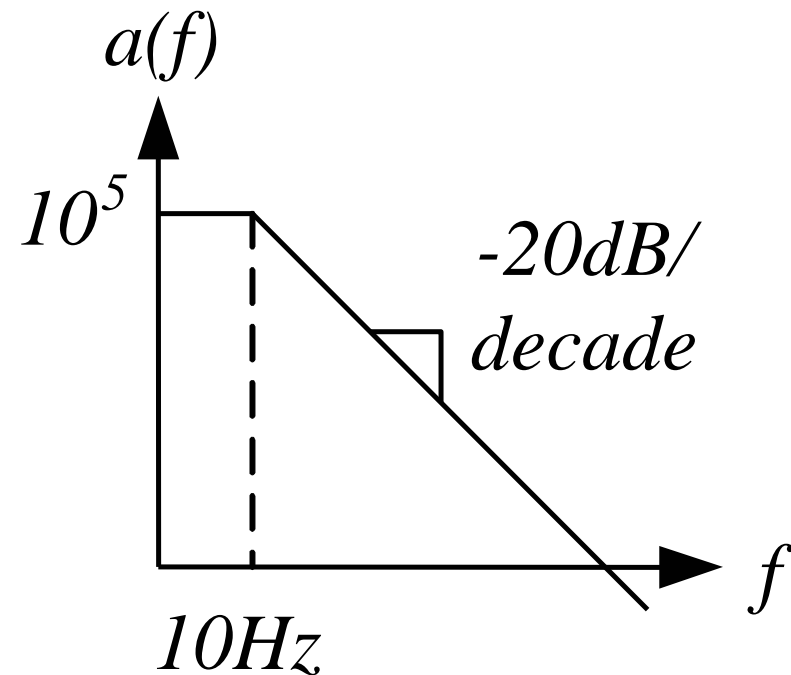
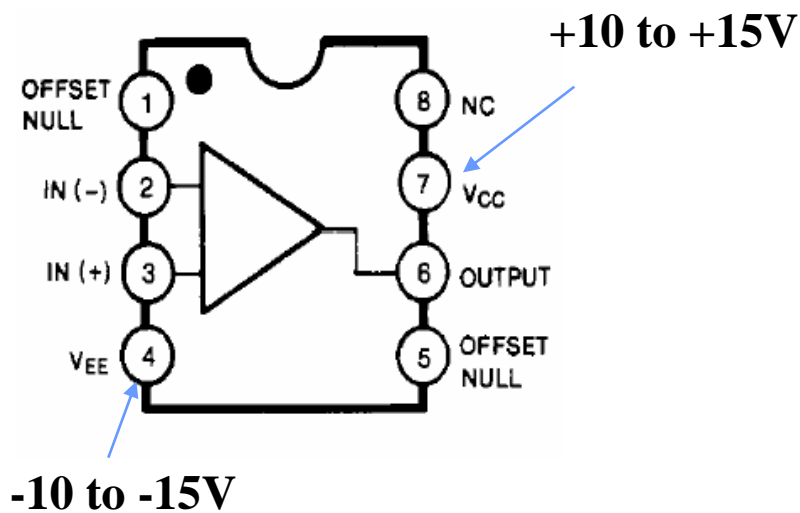
DC Model



- Typically very high input resistance $\sim 300\text{K}\Omega$
- High DC gain ($\sim 10^5$)
- Output resistance $\sim 75\Omega$

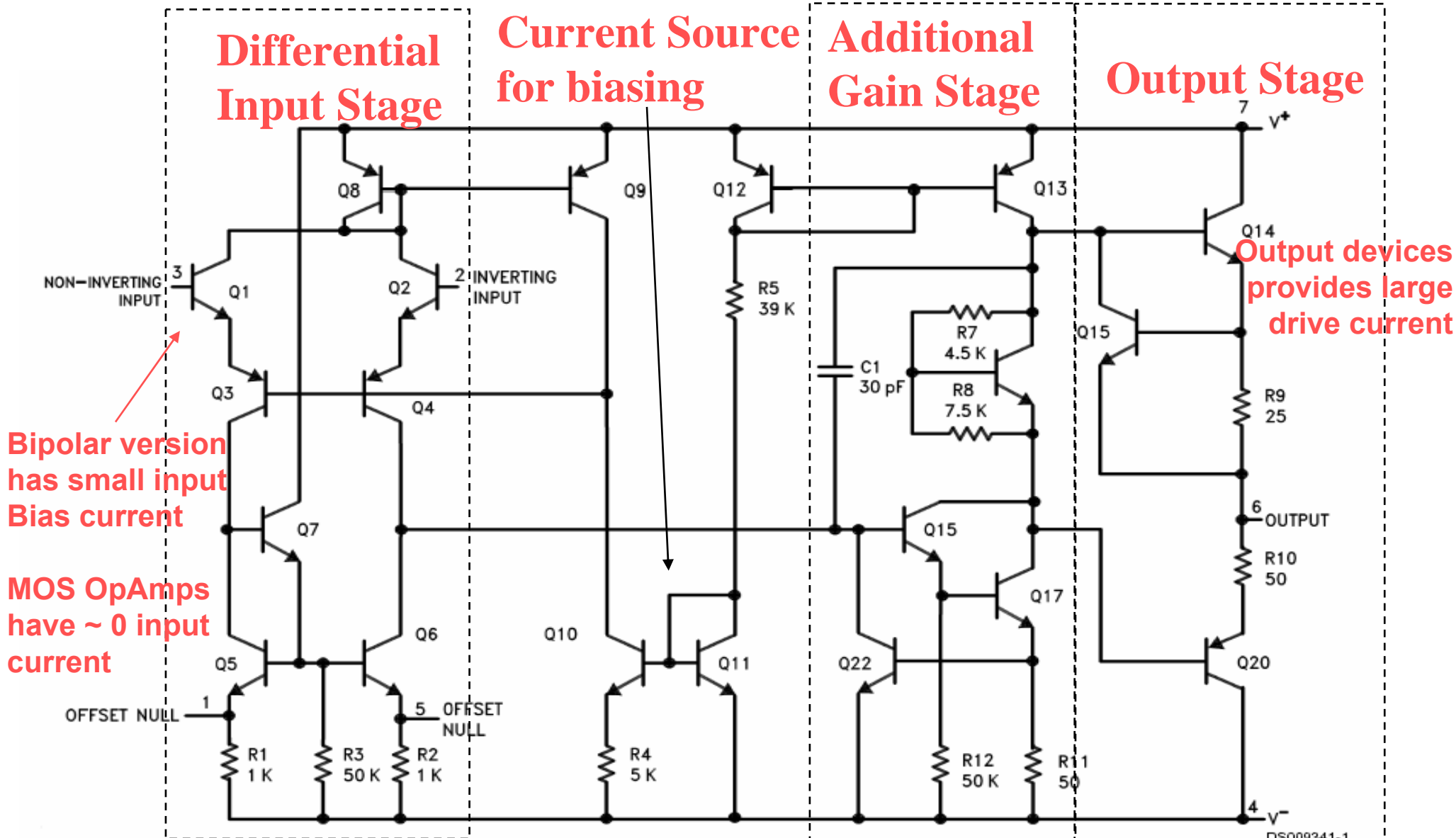
$$V_{out} = a(f) \cdot V_{in}$$

LM741 Pinout





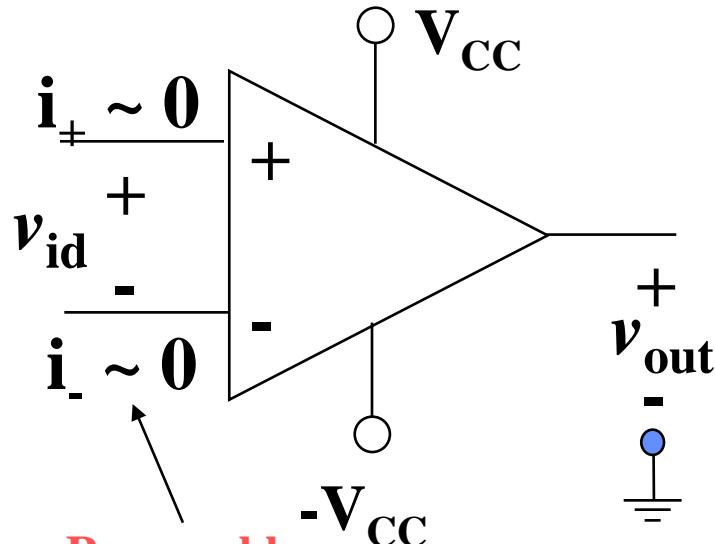
The Inside of a 741 OpAmp



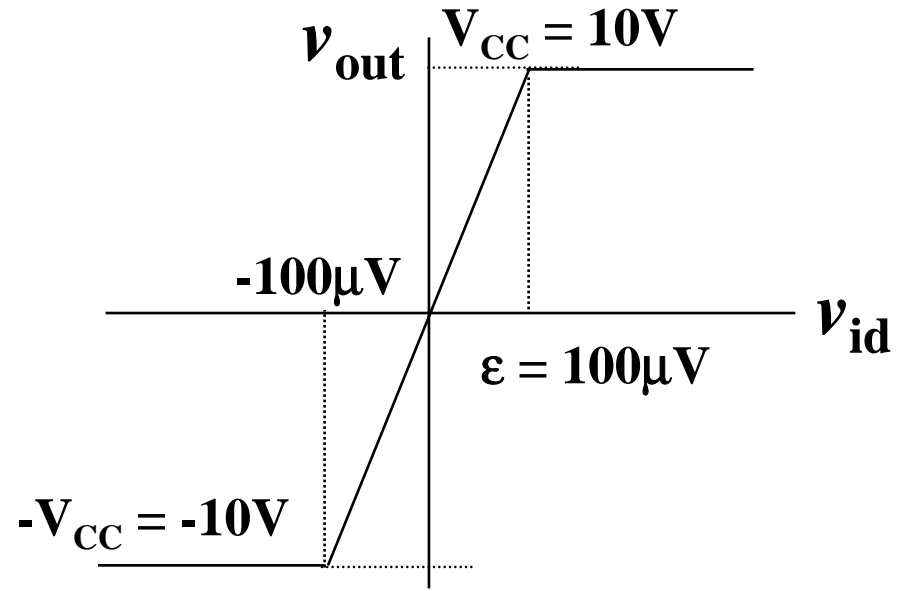
Gain is Sensitive to Operating Condition (e.g., Device, Temperature, Power supply voltage, etc.)



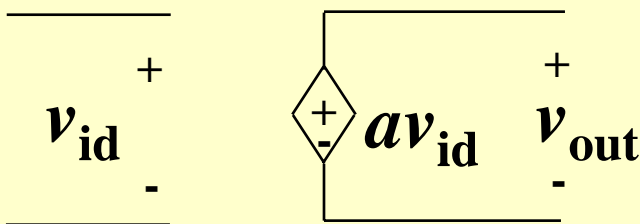
Simple Model for an OpAmp



Reasonable approximation

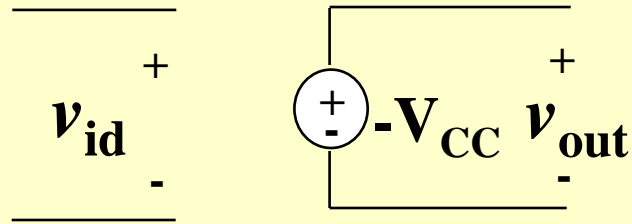


Linear Mode



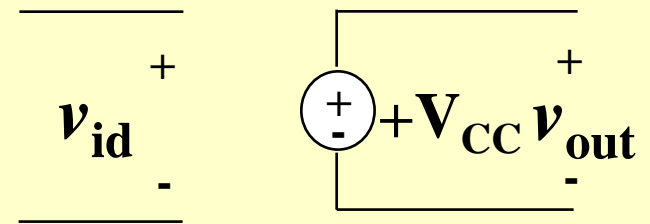
$$\text{If } -V_{CC} < v_{out} < V_{CC}$$

Negative Saturation



$$v_{id} < -\epsilon$$

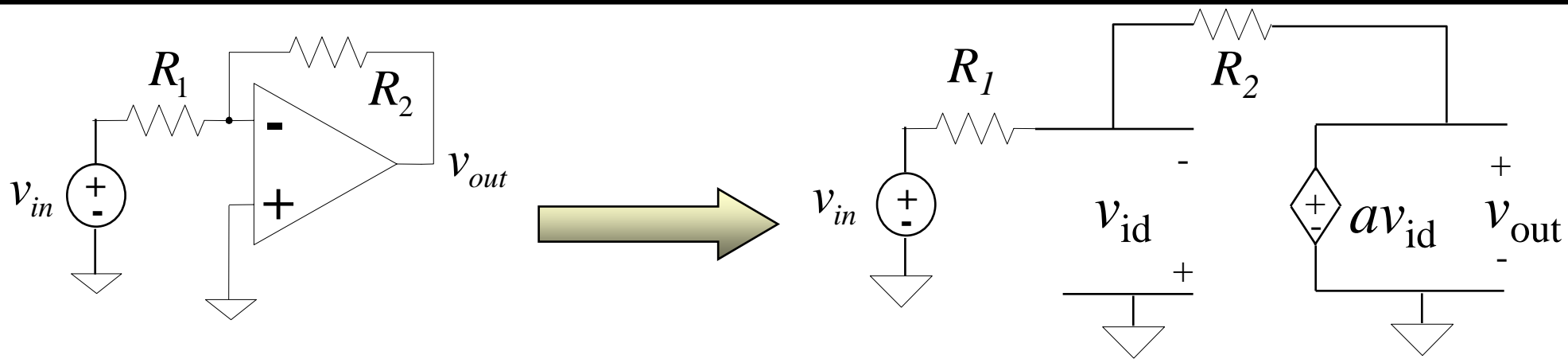
Positive Saturation



$$v_{id} > \epsilon$$

Small input range for “Open” loop Configuration

The Power of (Negative) Feedback



$$\frac{v_{in} + v_{id}}{R_1} + \frac{v_{out} + v_{id}}{R_2} = 0 \quad v_{id} = \frac{v_{out}}{a} \quad \frac{v_{in}}{R_1} = -\frac{v_{out}}{a} \left[\frac{1}{R_1} + \frac{a}{R_2} + \frac{1}{R_2} \right]$$

$$\frac{v_{out}}{v_{in}} = -\frac{R_2 a}{(1+a)R_1 + R_2} \approx -\frac{R_2}{R_1} \text{ (if } a \gg 1)$$

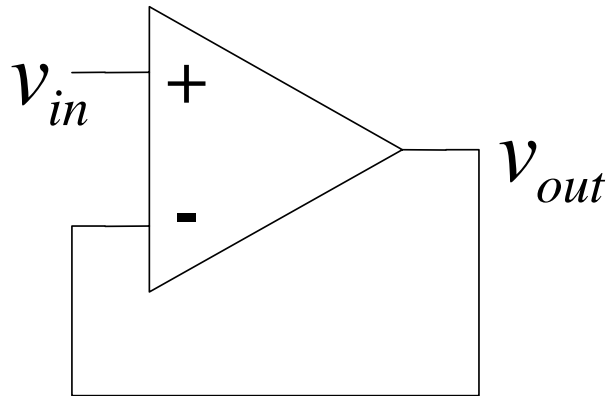
- Overall (closed loop) gain does not depend of open loop gain
- **Trade gain for robustness**
- Easier analysis approach: **“virtual short circuit approach”**
 - $v_+ = v_- = 0$ if OpAmp is linear



Basic OpAmp Circuits

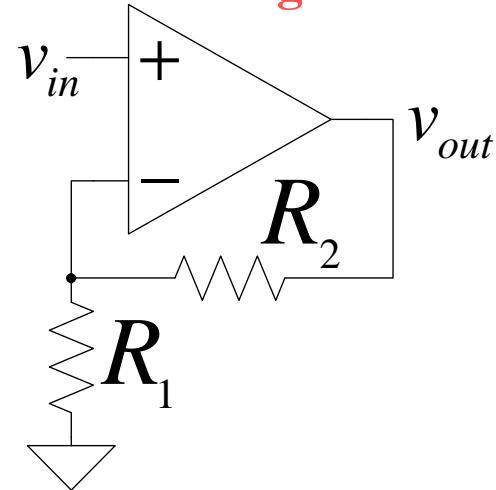


Voltage Follower (buffer)



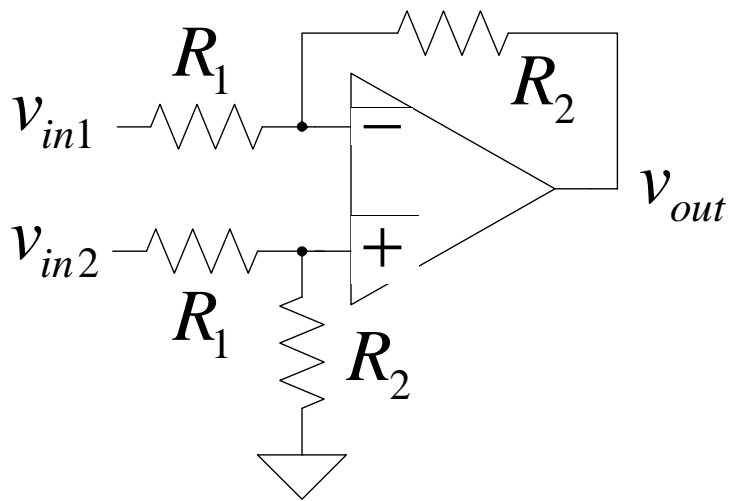
$$V_{out} \approx V_{in}$$

Non-inverting



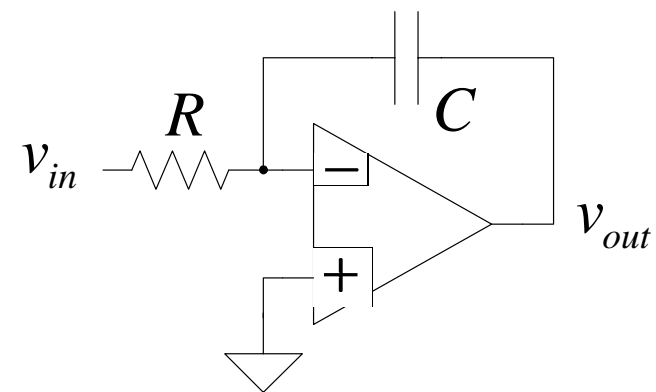
$$V_{out} \approx \frac{R_1 + R_2}{R_1} V_{in}$$

Differential Input



$$V_{out} \approx \frac{R_2}{R_1} (V_{in2} - V_{in1})$$

Integrator



$$V_{out} \approx -\frac{1}{RC} \int_{-\infty}^t V_{in} dt$$



Use With Open Loop



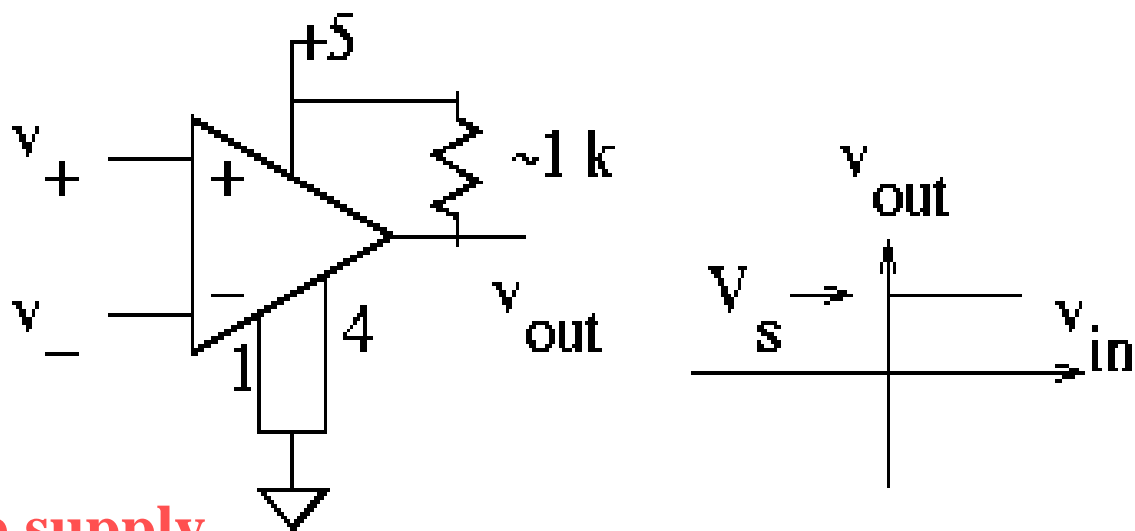
Analog Comparator:

Is $V_+ > V_-$?

The Output is a **DIGITAL** signal

Analog Comparator: Analog to TTL

LM 311 Needs Pull-Up

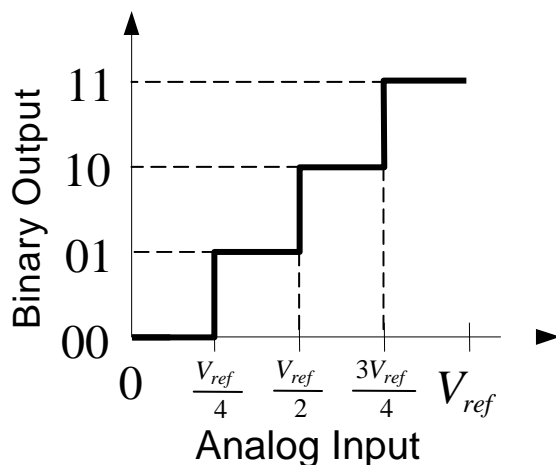


LM311 is a single supply comparator

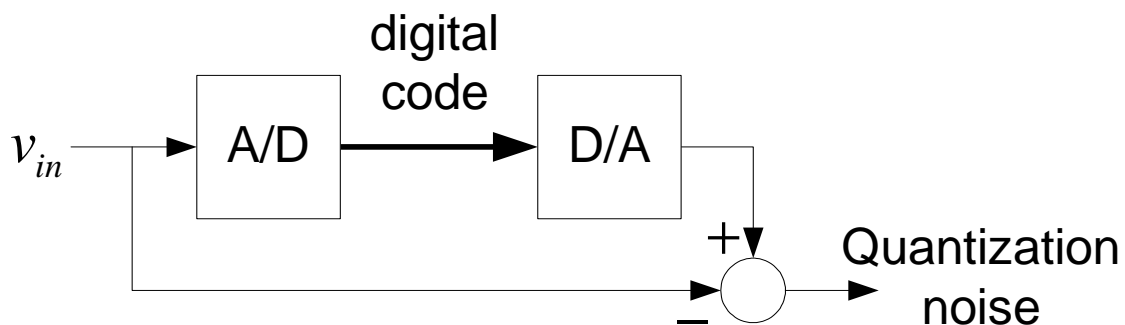
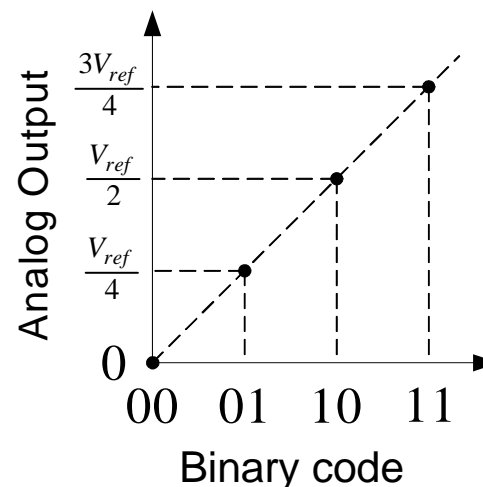
Data Conversion: Quantization Noise



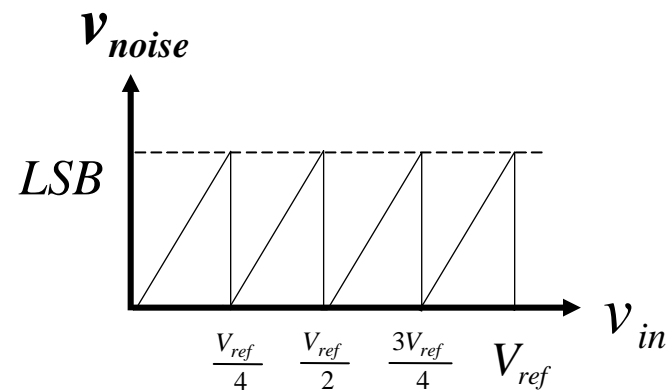
A/D Conversion



D/A Conversion



- Quantization noise exists even with *ideal* A/D and D/A converters

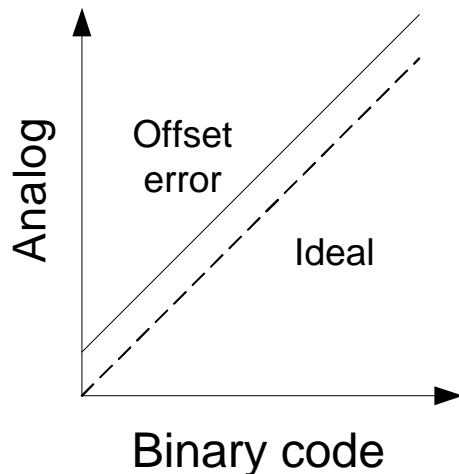




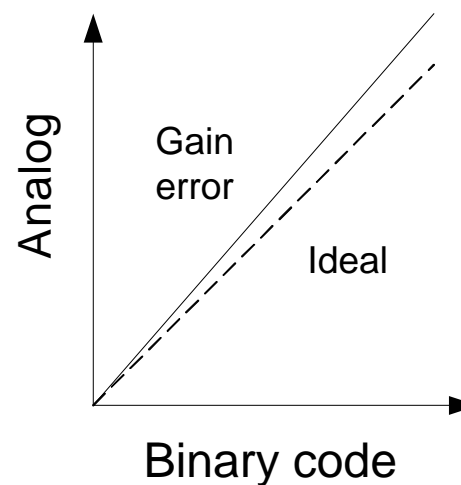
Non-idealities in Data Conversion



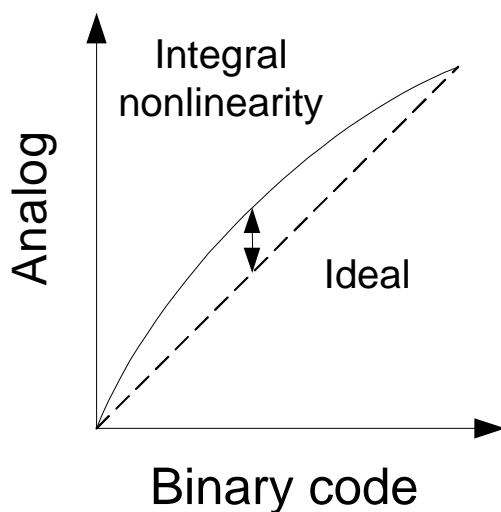
Offset – a constant voltage offset that appears at the output when the digital input is 0



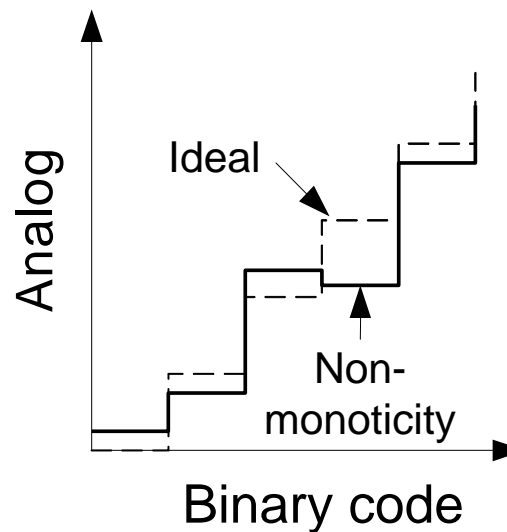
Gain error – deviation of slope from ideal value of 1



Integral Nonlinearity – maximum deviation from the ideal analog output voltage

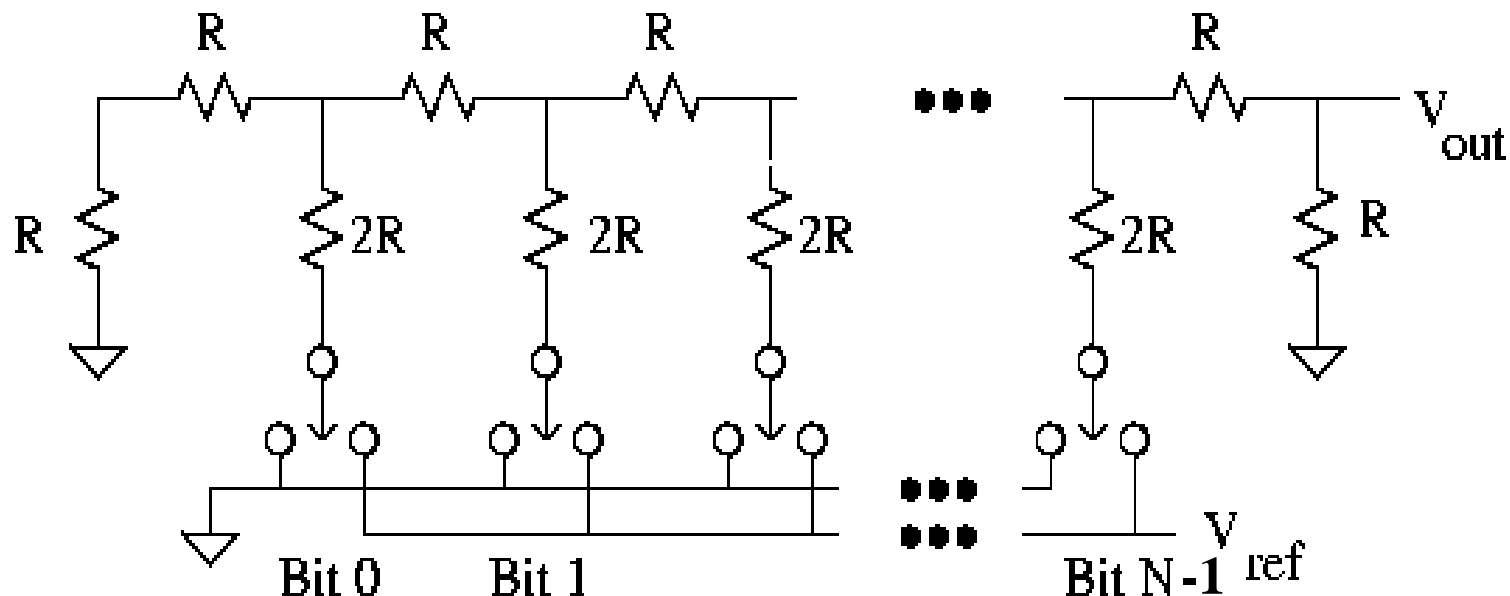
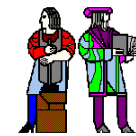


Differential nonlinearity – the largest increment in analog output for a 1-bit change





R-2R Ladder DAC Architecture

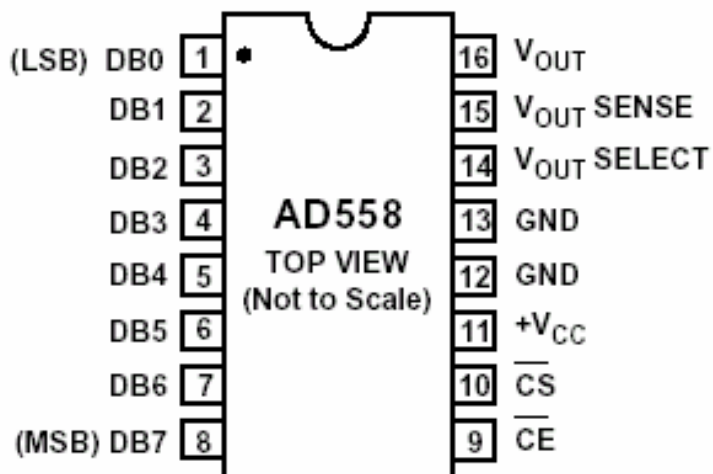


$$V_{out} = \frac{1}{6} V_{ref} \left[B_7 + \frac{1}{2} B_6 + \frac{1}{4} B_5 + \dots + \frac{1}{128} B_0 \right]$$

- Note that the driving point impedance (resistance) is the same for each cell.
- R-2R Ladder achieves large current division ratios with only two resistor values



DAC (AD 558) Specs - Used in Lab 3



Input Logic Coding

Digital Input Code			Output Voltage	
Binary	Hexadecimal	Decimal	2.56 V Range	10.000 V Range
0000 0000	00	0	0	0
0000 0001	01	1	0.010 V	0.039 V
0000 0010	02	2	0.020 V	0.078 V
0000 1111	0F	15	0.150 V	0.586 V
0001 0000	10	16	0.160 V	0.625 V
0111 1111	7F	127	1.270 V	4.961 V
1000 0000	80	128	1.280 V	5.000 V
1100 0000	C0	192	1.920 V	7.500 V
1111 1111	FF	255	2.55 V	9.961 V

- 8-bit DAC
- Single Supply Operation: 5V to 15V
- Integrates required references (bandgap voltage reference)
- Uses a R-2R resistor ladder
- Settling time 1 μ s
- Programmable output range from 0V to 2.56V or 0V to 10V
- Simple Latch based interface

Chip Architecture and Interface

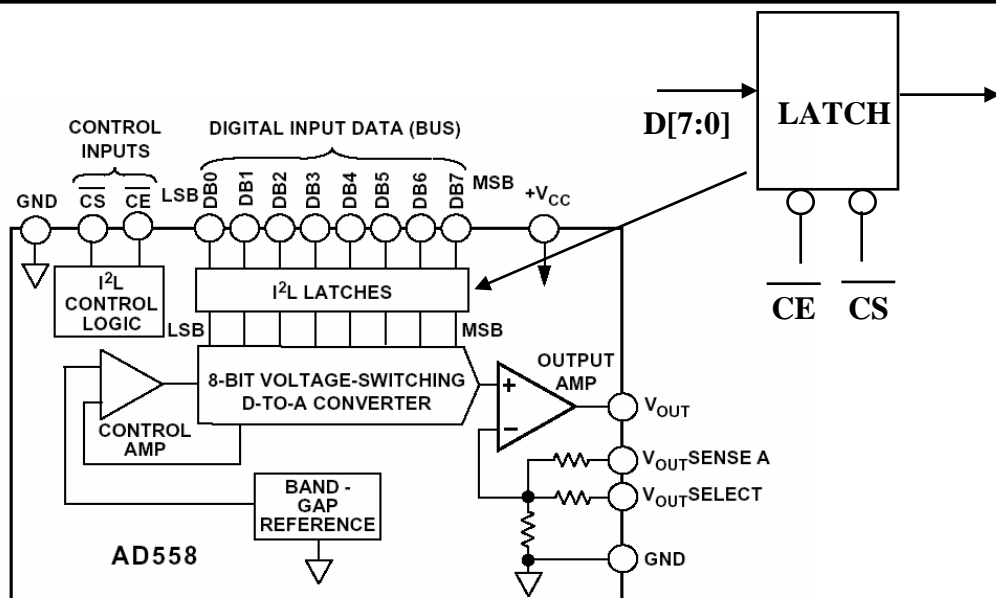
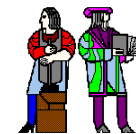


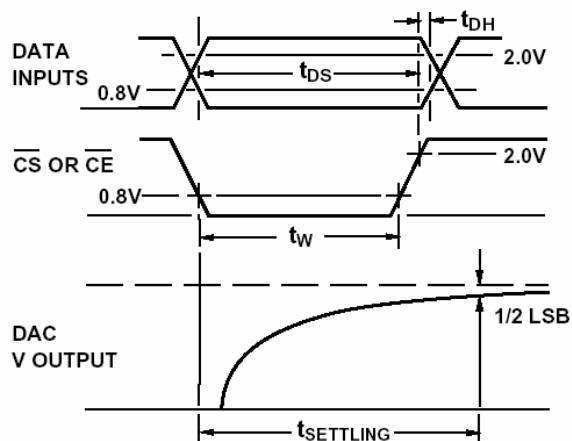
Table I. AD558 Control Logic Truth Table

Input Data	\overline{CE}	\overline{CS}	DAC Data	Latch Condition
0	0	0	0	“Transparent”
1	0	0	1	“Transparent”
0	g	0	0	Latching
1	g	0	1	Latching
0	0	g	0	Latching
1	0	g	1	Latching
X	1	X	Previous Data	Latched
X	X	1	Previous Data	Latched

NOTES

X = Does not matter.

g = Logic Threshold at Positive-Going Transition.



t_w = STORAGE PULSE WIDTH = 200ns MIN
 t_{DH} = DATA HOLD TIME = 10ns MIN
 t_{DS} = DATA SETUP TIME = 200ns MIN
 $t_{SETTLING}$ = DAC OUTPUT SETTLE TIME TO $\pm 1/2$ LSB

Outputs are noisy when input bits settles, so it is best to have inputs stable before latching the input data

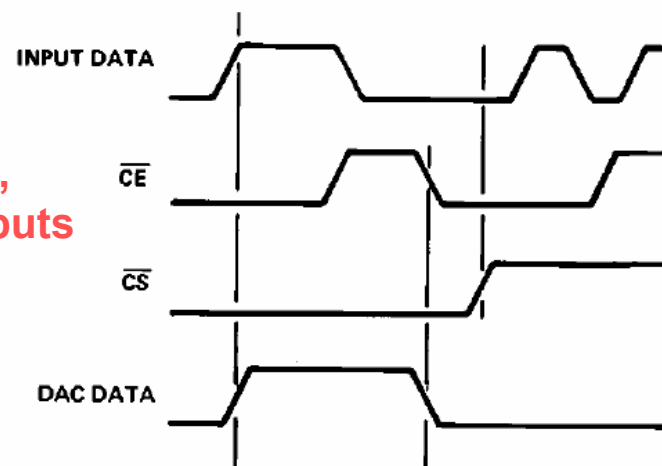
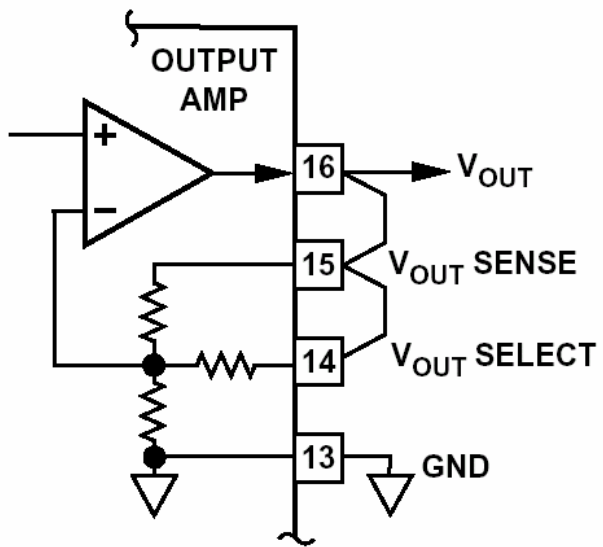


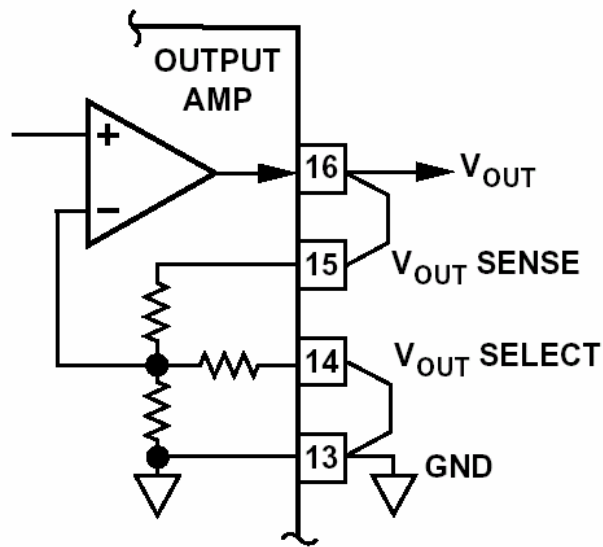
Figure 6. AD558 Control Logic Function



Setting the Voltage Range



a. 0 V to 2.56 V Output Range



b. 0 V to 10 V Output Range

Very similar to a non-inverting amp

Strap output for different voltage ranges

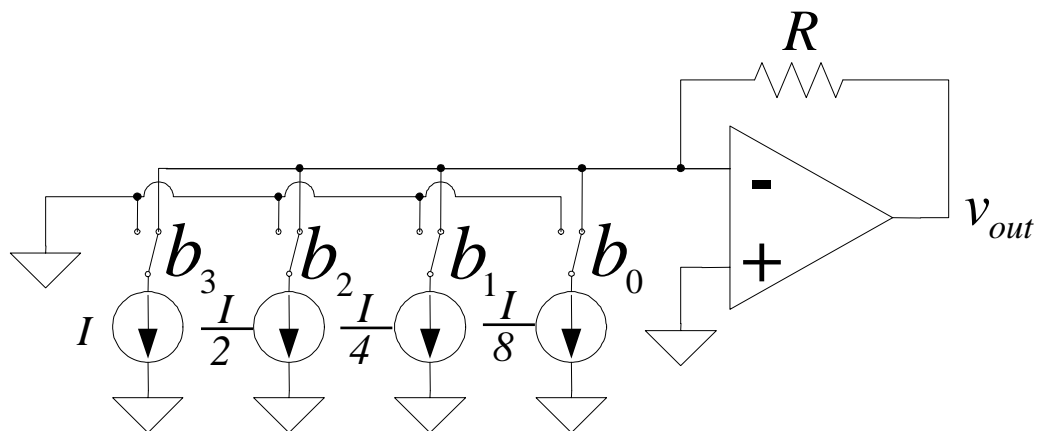
Input Logic Coding

Digital Input Code			Output Voltage	
Binary	Hexadecimal	Decimal	2.56 V Range	10.000 V Range
0000 0000	00	0	0	0
0000 0001	01	1	0.010 V	0.039 V
0000 0010	02	2	0.020 V	0.078 V
0000 1111	0F	15	0.150 V	0.586 V
0001 0000	10	16	0.160 V	0.625 V
0111 1111	7F	127	1.270 V	4.961 V
1000 0000	80	128	1.280 V	5.000 V
1100 0000	C0	192	1.920 V	7.500 V
1111 1111	FF	255	2.55 V	9.961 V

Convert data to Offset binary



Another Approach: Binary-Weighted DAC

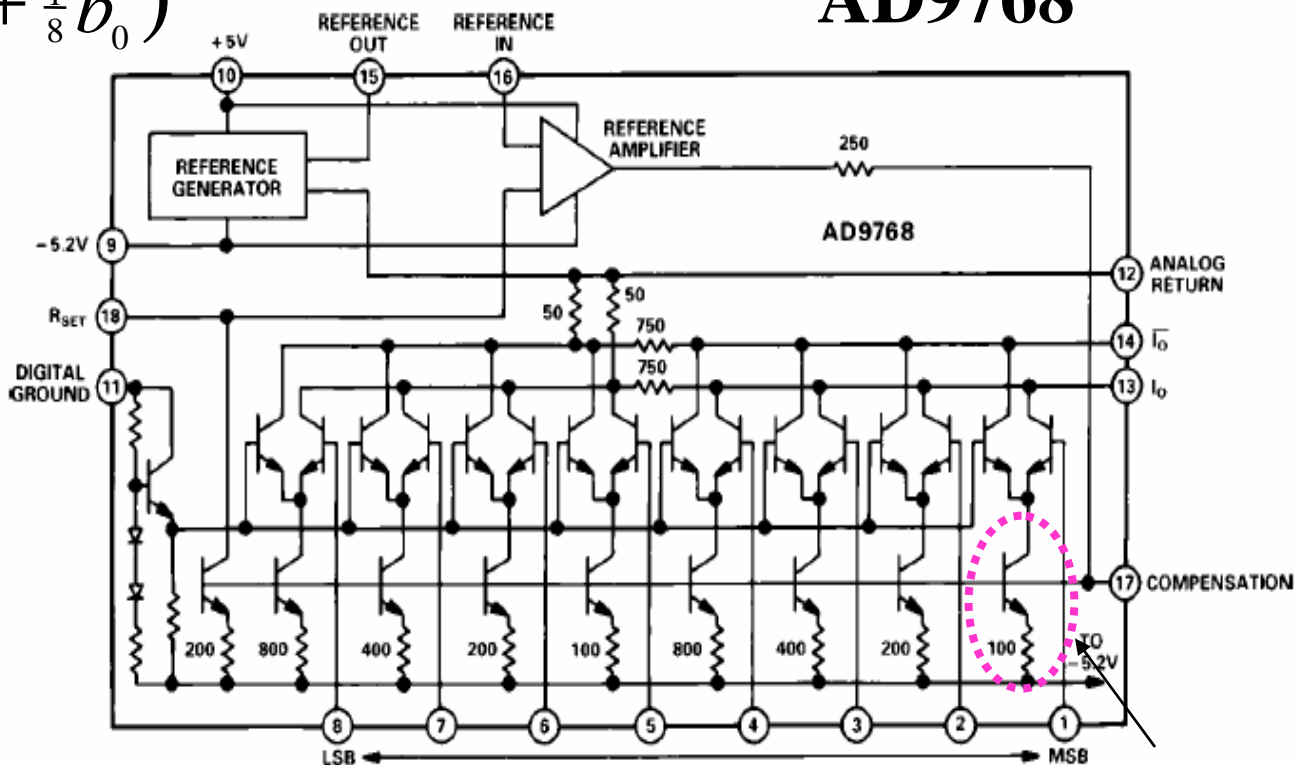


- Switch binary-weighted currents
- MSB to LSB current ratio is 2^N

$$v_{out} = -IR\left(b_3 + \frac{1}{2}b_2 + \frac{1}{4}b_1 + \frac{1}{8}b_0\right)$$

- Analog Devices AD9768 uses two banks of ratioed currents
- Additional current division performed by 750Ω resistor between the two banks

AD9768



Reference current source

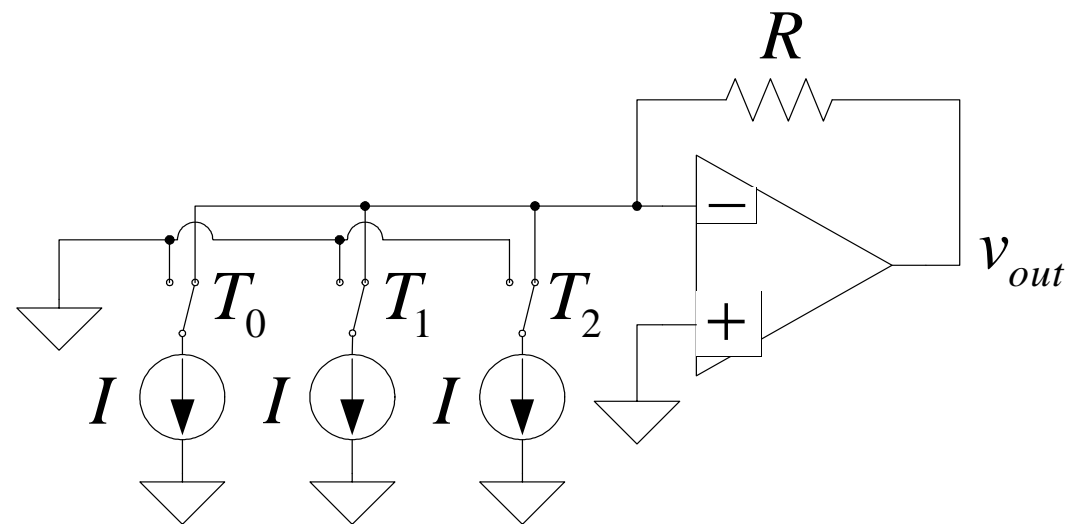
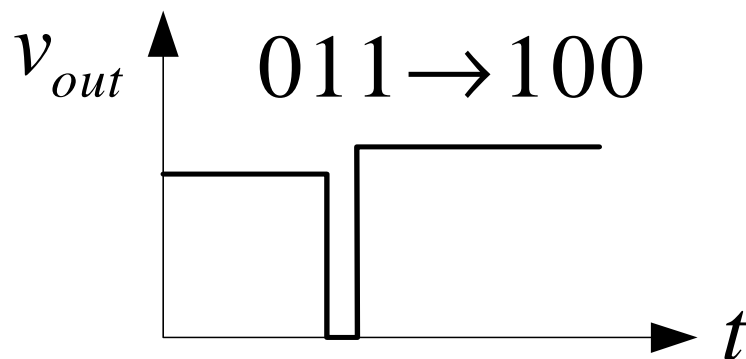


Glitching and Thermometer D/A



- Glitching is caused when switching times in a D/A are not synchronized
- Example: Output changes from 011 to 100 – MSB switch is delayed
- Filtering reduces glitch but increases the D/A settling time
- One solution is a thermometer code D/A – requires $2^N - 1$ switches but no ratioed currents

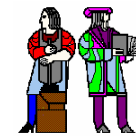
Binary		Thermometer		
0	0	0	0	0
0	1	0	0	1
1	0	0	1	1
1	1	1	1	1



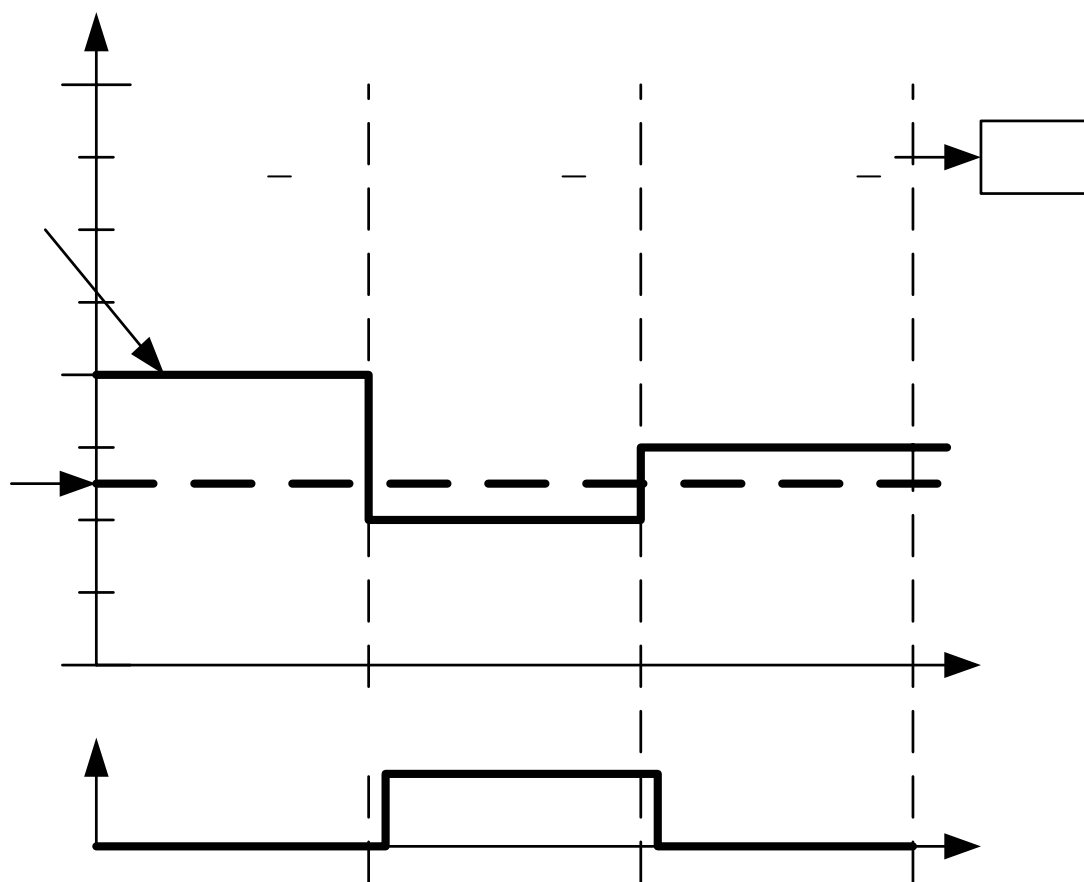
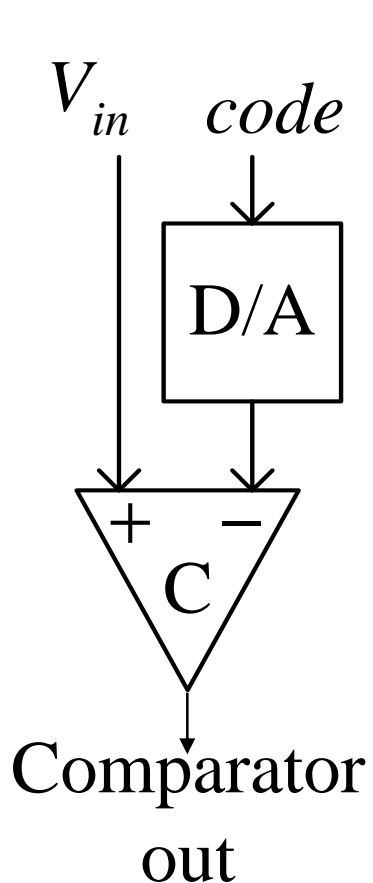
$$v_{out} = -IR(T_0 + T_1 + T_2)$$



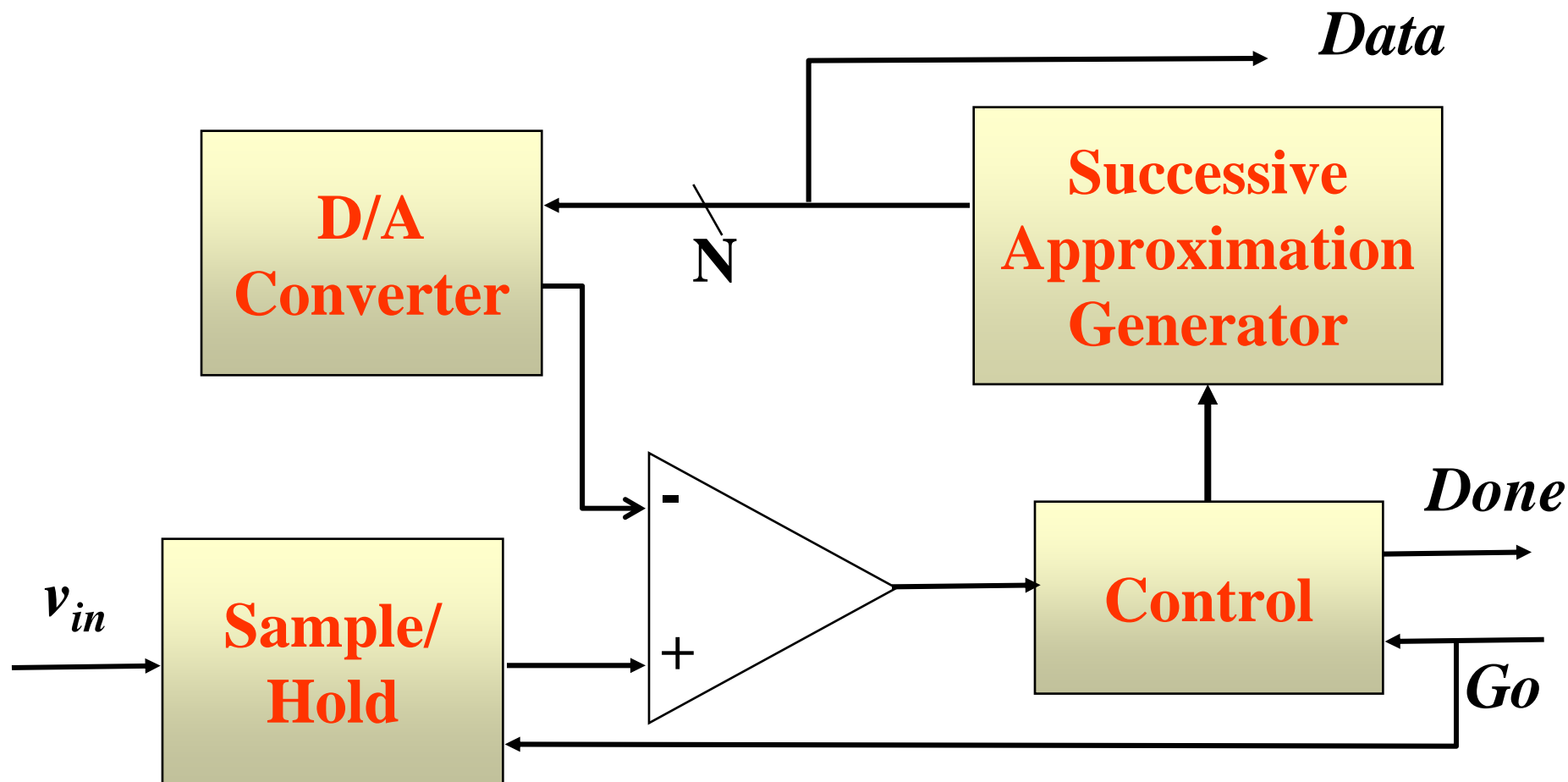
Successive-Approximation A/D



- **D/A converters are typically compact and easier to design. Why not A/D convert using a D/A converter and a comparator?**
- **D to A generates analog voltage which is compared to the input voltage**
- **If D to A voltage > input voltage then set that bit; otherwise, reset that bit**
- **This type of A to D takes a fixed amount of time proportional to the bit length**



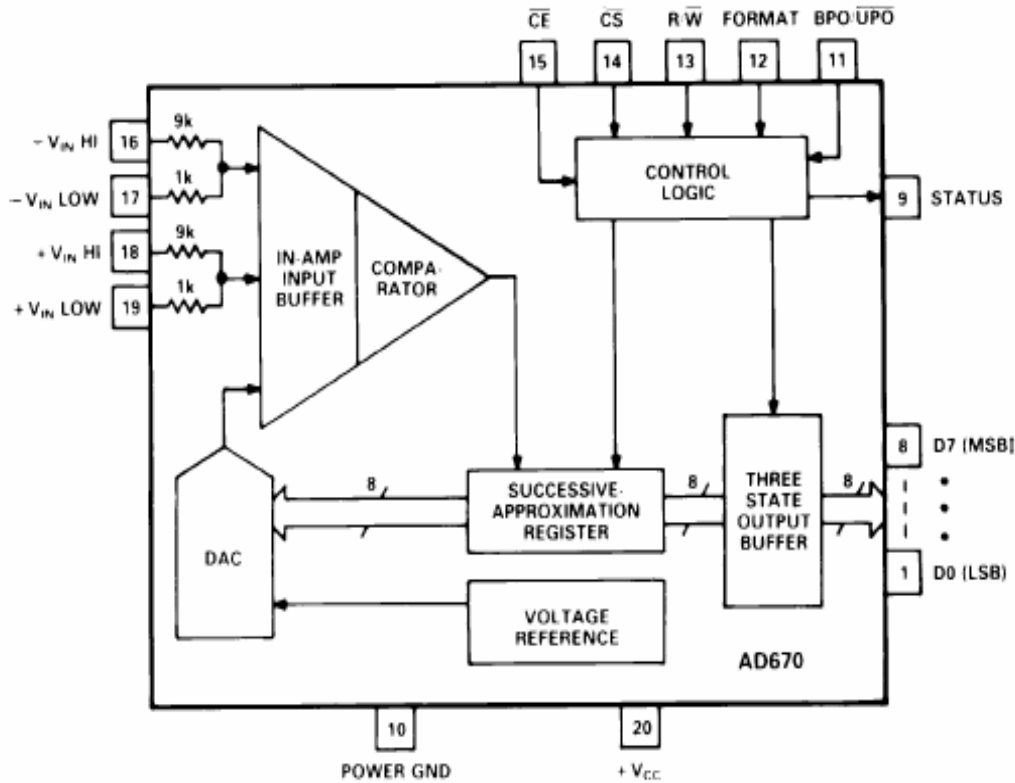
Successive-Approximation A/D



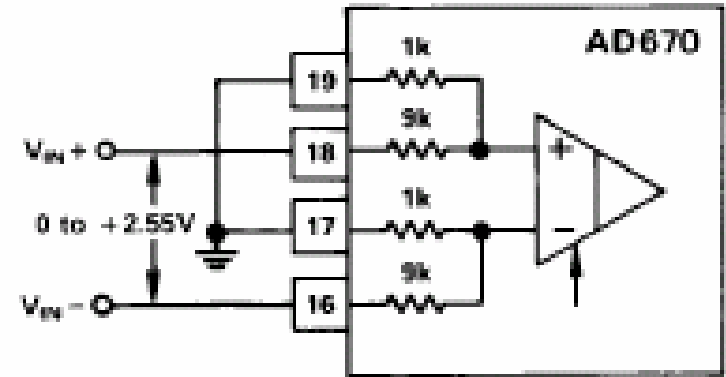
- Serial conversion takes a time equal to $N(t_{D/A} + t_{comp})$



Successive-Approximation A/D (AD670) – Used in Lab 3

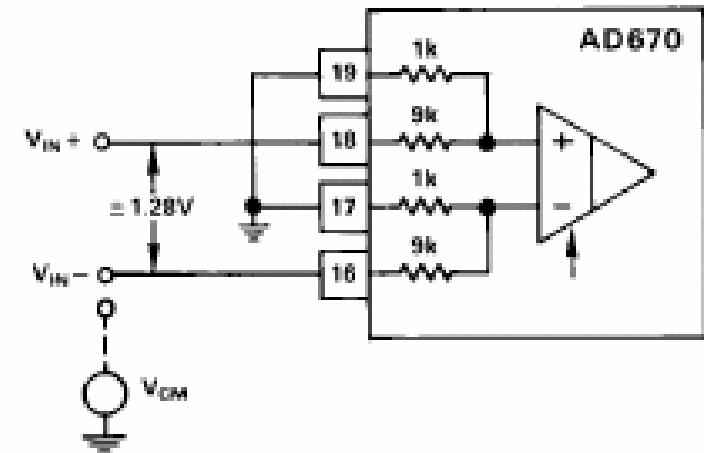


Unipolar (BPO = 0)



2a. 0 V to 2.55 V (10 mV/LSB)

Bipolar (BPO = 1)

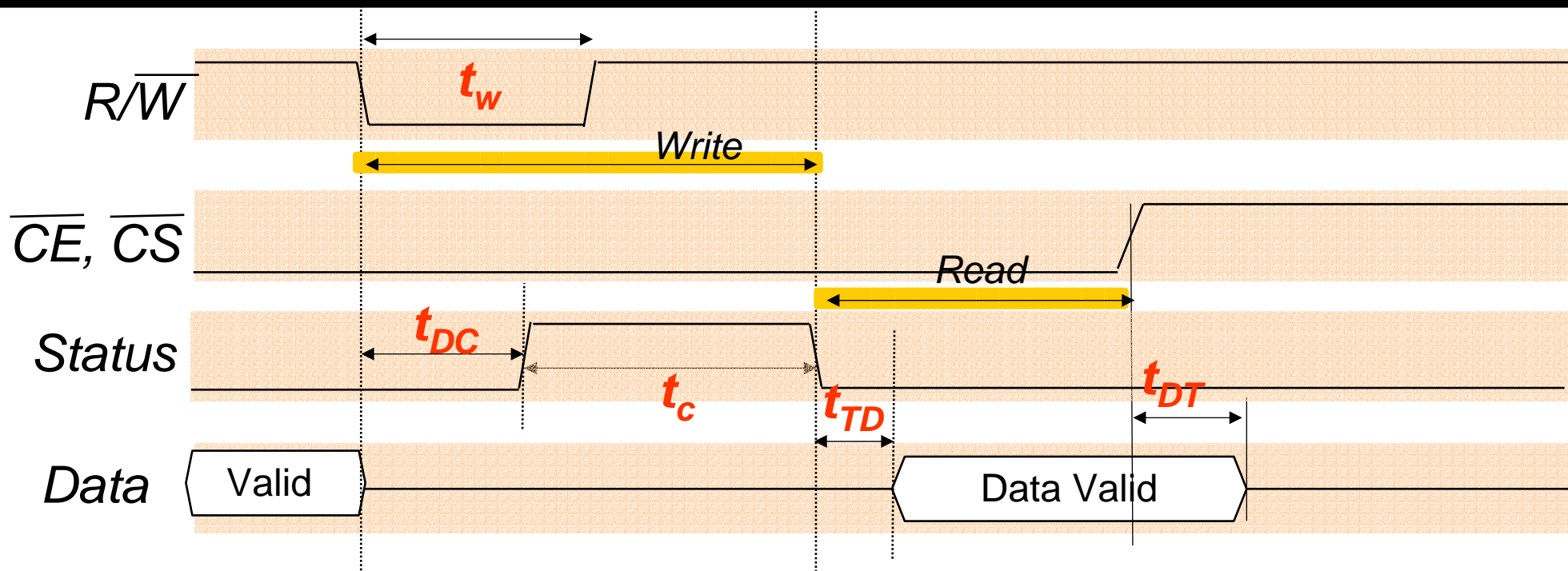


3a. ± 1.28 V Range

BPO/ \overline{UPO}	FORMAT	INPUT RANGE/ OUTPUT FORMAT
0	0	Unipolar/Straight Binary
1	0	Bipolar/Offset Binary
0	1	Unipolar/2s Complement
1	1	Bipolar/2s Complement



Single Write, Single Read Operation (see data sheet for other modes)



t_w (write/start pulse width) = 300ns (min)

t_{DC} (delay to start conversion) = 700ns (max)

t_c (conversion time) = 10 μ s (max)

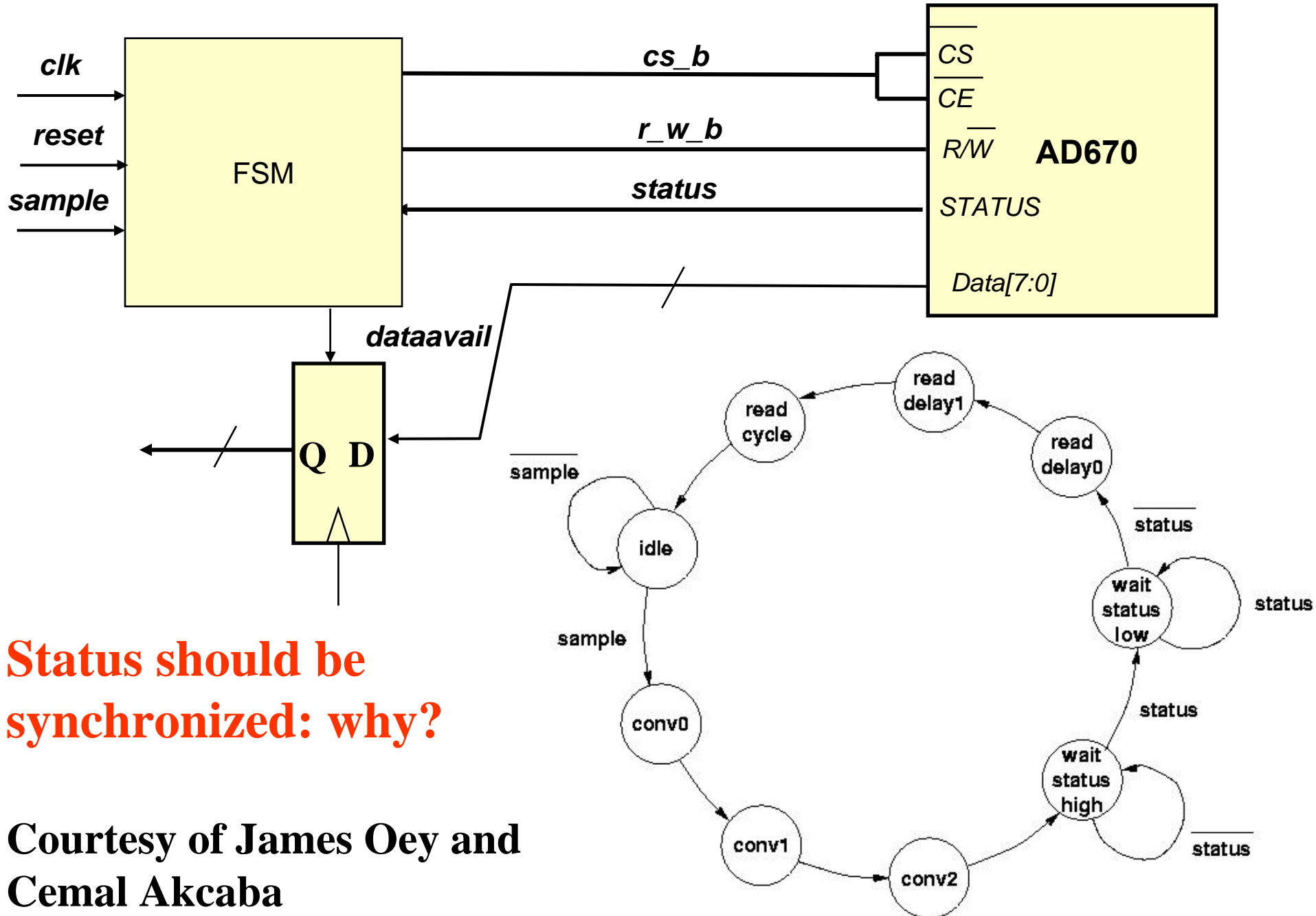
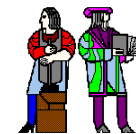
t_{TD} (Bus Access Time) = 250 (max)

t_{DT} (Output Float Delay) = 150 (max)

- Control bits \overline{CE} and \overline{CS} can be wired to ground if A/D is the only chip driving the bus
- Tie the \overline{CE} and \overline{CS} pins together for lab3 and hardwire BPO and Format



Simple A/D Interface FSM

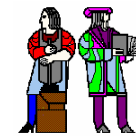


Status should be synchronized: why?

Courtesy of James Oey and Cemal Akcaba



Example A/D Verilog Interface



```
module AD670 (clk, reset, sample, dataavail,  
r_wbar, cs_bar, status, state);  
  
    // System Clk  
    input clk;  
    // Global Reset signal, assume it is synchronized  
  
    input reset;  
  
    // User Interface  
    input sample;  
    output dataavail;  
  
    // A-D Interface  
    input status;  
    reg status_d1, status_d2;  
    output r_wbar, cs_bar;  
    output [3:0] state;  
  
    // internal state  
    reg [3:0] state;  
    reg [3:0] nextstate;  
    reg r_wbar_int, r_wbar;  
    reg cs_bar_int, cs_bar;  
    reg dataavail;
```

1/5

```
    // State declarations.  
    parameter IDLE = 0;  
    parameter CONV0 = 1;  
    parameter CONV1 = 2;  
    parameter CONV2 = 3;  
    parameter WAITSTATUSHIGH = 4;  
    parameter WAITSTATUSLOW = 5;  
    parameter READDELAY0 = 6;  
    parameter READDELAY1 = 7;  
    parameter READCYCLE = 8;  
  
    always @ (posedge clk or negedge reset)  
    begin  
        if (!reset) state <=IDLE;  
        else state <=nextstate;  
  
        status_d1 <= status;  
        status_d2 <= status_d1;  
  
        r_wbar <= r_wbar_int;  
        cs_bar <=cs_bar_int;  
  
    end
```

2/5



Example A/D Verilog Interface (cont.)



```
always @ (state or status_d2 or sample) begin
  // defaults
  r_wbar_int = 1; cs_bar_int = 1; dataavail = 0;

  case (state)

    IDLE: begin
      if(sample) nextstate = CONV0;
      else nextstate = IDLE;
      end

    CONV0:
      begin
        r_wbar_int = 0;
        cs_bar_int = 0;
        nextstate = CONV1;
      end

    CONV1:
      begin
        r_wbar_int = 0;
        cs_bar_int = 0;
        nextstate = CONV2;
      end
```

3/5

```
    CONV2:
      begin
        r_wbar_int = 0;
        cs_bar_int = 0;
        nextstate = WAITSTATUSHIGH;
      end

    WAITSTATUSHIGH:
      begin
        cs_bar_int = 0;
        if (status_d2) nextstate = WAITSTATUSLOW;

        else nextstate = WAITSTATUSHIGH;
      end

    WAITSTATUSLOW:
      begin
        cs_bar_int = 0;
        if (!status_d2) nextstate = READDELAY0;
        else nextstate = WAITSTATUSLOW;
      end
```

4/5



Example A/D Verilog Interface(cont.)



```
READDELAY0:
  begin
    cs_bar_int = 0;
    nextstate = READDELAY1;
  end

READDELAY1:
  begin
    cs_bar_int = 0;
    nextstate = READCYCLE;
  end

READCYCLE:
  begin
    cs_bar_int = 0;
    dataavail = 1;
    nextstate = IDLE;
  end

  default: nextstate = IDLE;
endcase // case(state)
end // always @ (state or status or sample)
endmodule // adcInterface
```

5/5

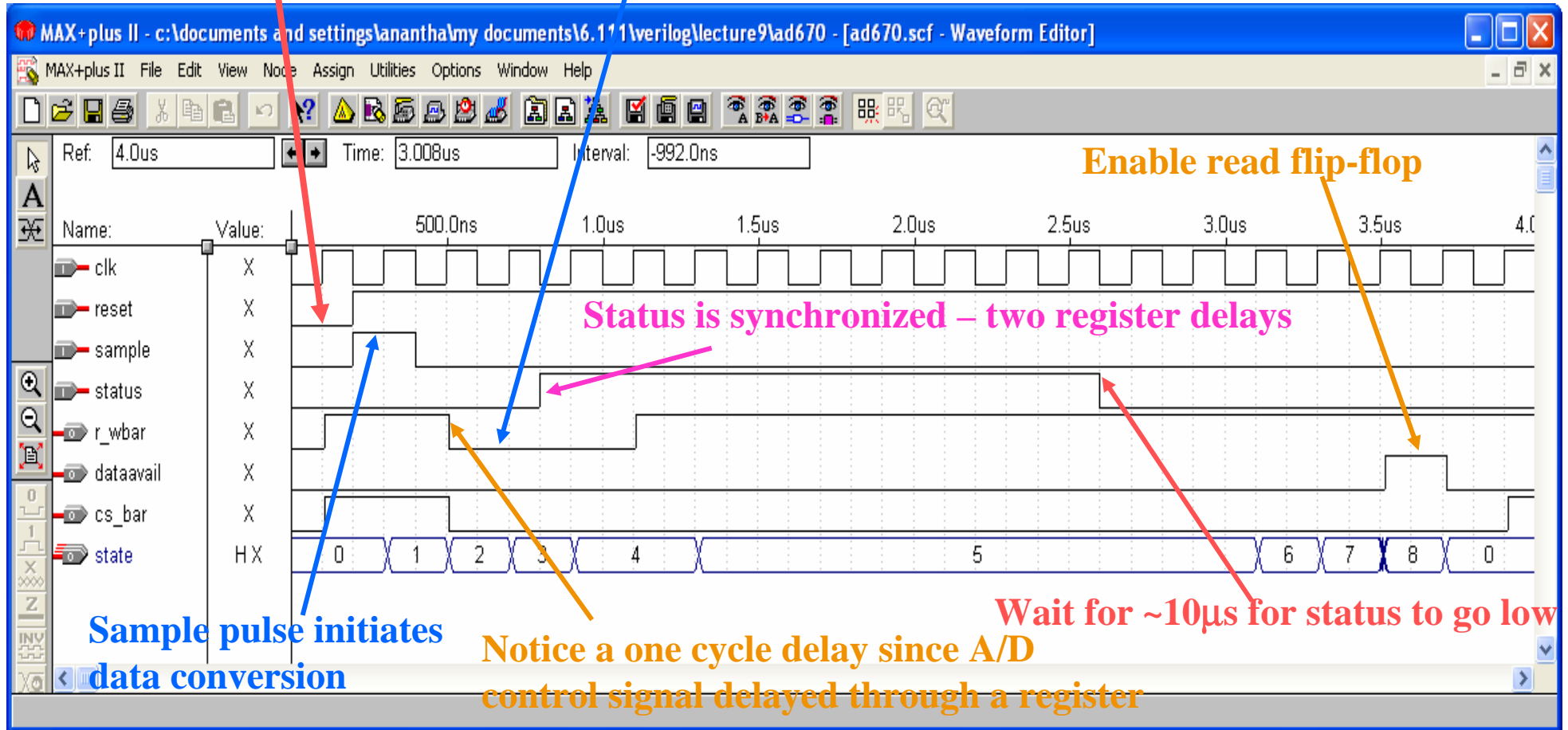


Simulation



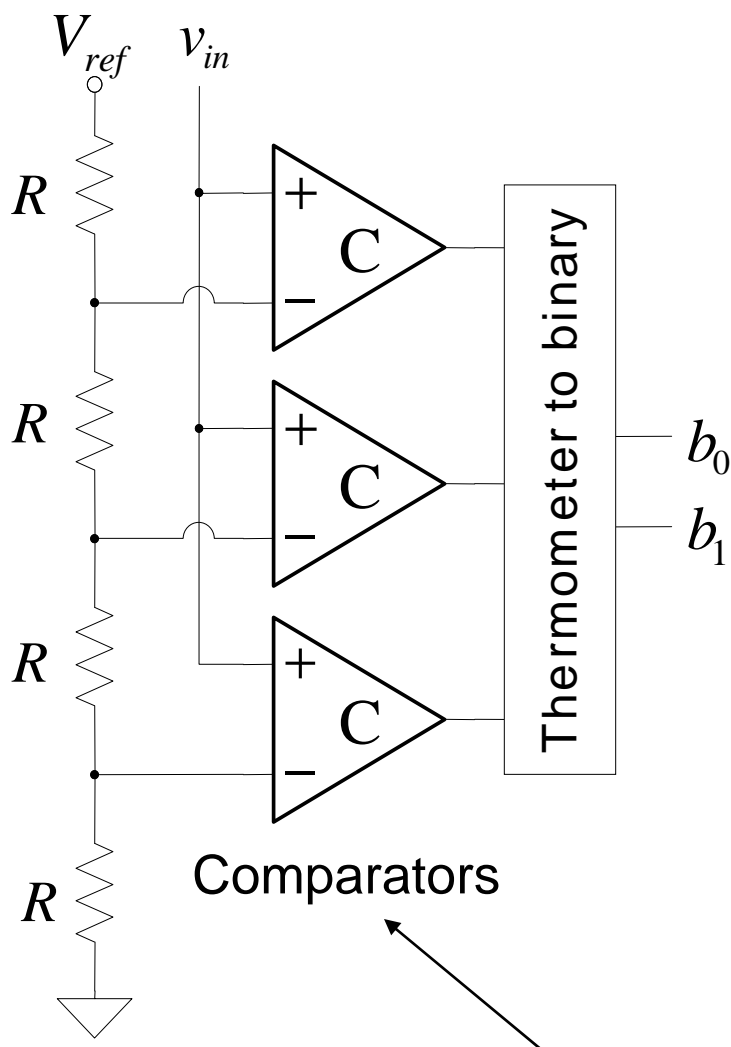
On reset, present state goes to 0

r_w_b must stay low for at least 3 cycles (@ 100ns period) – Don't need 3 cycles if you use the 1.8432MHz clock





Flash A/D Converter

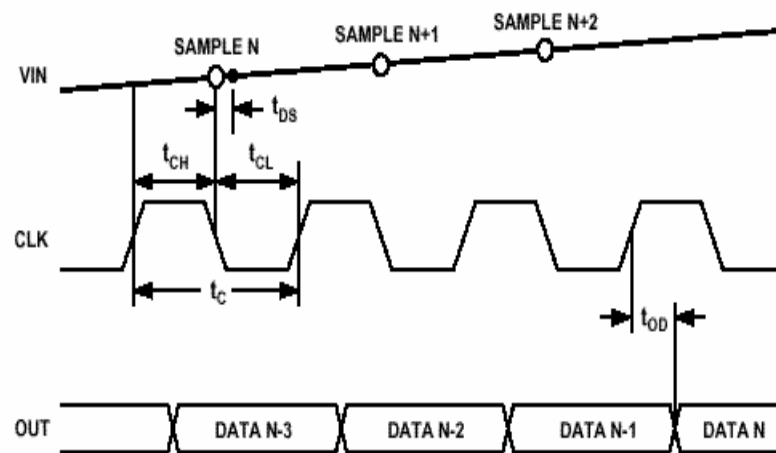
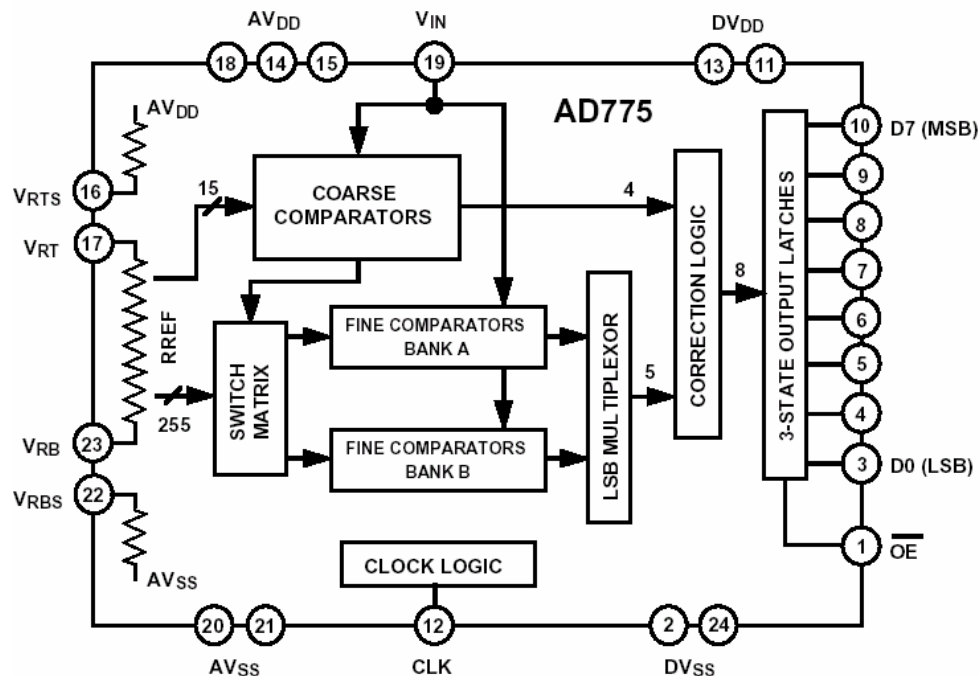


- Brute-force A/D conversion
- Simultaneously compare the analog value with every possible reference value
- Fastest method of A/D conversion
- **Size scales exponentially with precision** (requires 2^N comparators)

Another example of OpAmp in open loop



AD 775 – Flash Data Converter



TIMING SPECIFICATIONS

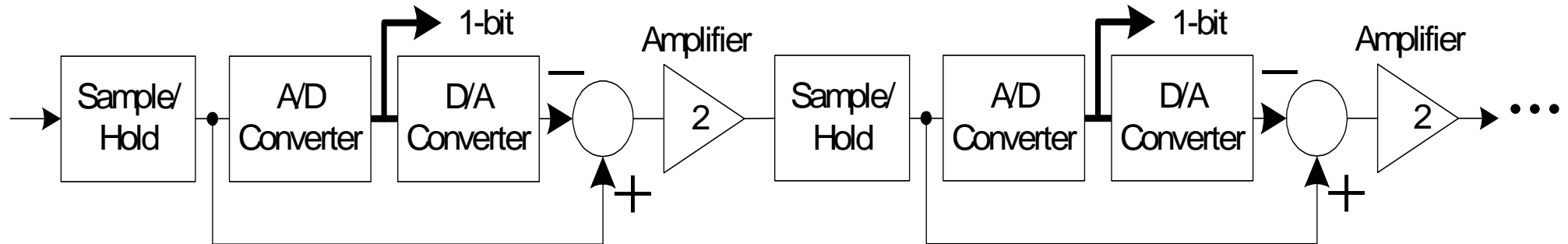
	Symbol	Min	Typ	Max	Units
Maximum Conversion Rate		20	35		MHz
Clock Period	t_c	50			ns
Clock High	t_{CH}	25			ns
Clock Low	t_{CL}	25			ns
Output Delay	t_{OD}		18	30	ns
Pipeline Delay (Latency)				2.5	Clock Cycles
Sampling Delay	t_{DS}		4		ns
Aperture Jitter			30		ps



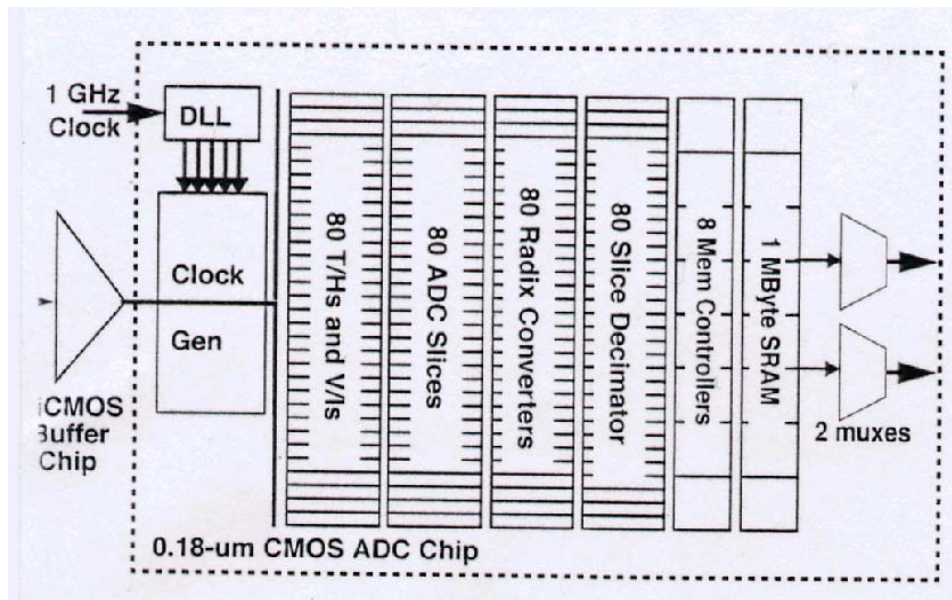
High Performance Converters: Use Pipelining and Parallelism!



Pipelining (used in video rate, RF basestations, etc.)



Parallelism (use many slower A/D's in parallel to build very high speed A/D converters)



[ISSCC 2003],
Poulton et. al.

**20Gsample/sec,
8-bit ADC
from Agilent Labs**



Summary of Analog Blocks



- **Analog blocks are integral components of any system. Need data converters (analog to digital and digital to analog), analog processing (OpAmps circuits, switched capacitors filters, etc.), power converters (e.g., DC-DC conversion), etc.**
- **We looked at example interfaces for A/D and D/A converters**
 - **Make sure you register critical signals (enables, $\overline{R/W}$, etc.)**
- **Analog design incorporate digital principles**
 - **Glitch free operation using coding**
 - **Parallelism and Pipelining!**
 - **More advanced concepts such as calibration**